

Product / Process Change Notification



N° 2016-072-A

Dear Customer,

Please find attached our INFINEON Technologies PCN:

Introduction of an Additional Wafer Test Location at Infineon Technologies (Kulim) Sdn. Bhd, Kulim, Malaysia for Dedicated SFET4 100V Products

Important information for your attention:

- Please respond to this PCN by indicating your decision on the approval form, sign it and return to your sales partner before **15th November 2018**.
- Infineon aligns with the widely-recognized JEDEC STANDARD “**JESD46**“, which stipulates: **“Lack of acknowledgement of the PCN within 30 days constitutes acceptance of the change.”**

Your prompt reply will help Infineon Technologies to assure a smooth and well executed transition. If Infineon does not hear from your side by the due date, we will assume your full acceptance to this proposed change and its implementation.

Your attention and response to this matter is greatly appreciated.

Infineon Technologies AG
Postal Address Headquarters: Am Campeon 1-15, D-85579 Neubiberg, Phone +49 (0)89 234-0
Chairman of the Supervisory Board: Dr. Eckart Süner
Management Board: Dr. Reinhard Ploss (CEO), Dominik Asam, Dr. Helmut Gassel, Jochen Hanebeck
Registered Office: Neubiberg Commercial Register
Amtsgericht München HRB 126492

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► **Products affected:** Please refer to attached affected product list 1_cip16072_A

► **Detailed Change Information:**

Subject: Introduction of an additional wafer test in Kulim for dedicated SFET4 100V products.

Reason: Expansion of wafer test to assure continuity of supply and enable flexible testing.

Description:	<u>Old</u>	<u>New</u>
Wafer Test	■ Infineon Technologies AG, Regensburg, Germany	■ Infineon Technologies (Kulim) Sdn. Bhd, Kulim, Malaysia or Infineon Technologies AG, Regensburg, Germany

► **Product Identification:** Traceability is ensured by lot number.

► **Impact of Change:** No change in form fit or function and no impact on quality and reliability of the final product.
The wafer test location verification is performed via the Advanced Measurement System Analysis (AMSA) methodology.

► **Attachments:** Affected product list 1_cip16072_A

► **Time Schedule:**

- Final qualification report: Available on request
- First samples available: No samples planned due to no change of product.
- Intended start of delivery: 01-Februar-2019 or earlier after customer approval

If you have any questions, please do not hesitate to contact your local Sales office.

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Introduction of an Additional Wafer Test Location at Infineon Technologies
(Kulim) Sdn. Bhd, Kulim, Malaysia for Dedicated SFET4 100V Products



Sales Name	SP number	OPN	Package
IPB120N10S4-03	SP001102598	IPB120N10S403ATMA1	PG-TO263-3
IPB120N10S4-05	SP001102592	IPB120N10S405ATMA1	PG-TO263-3
IPB180N10S4-02	SP001057184	IPB180N10S402ATMA1	PG-TO263-7
IPB180N10S4-03	SP000915592	IPB180N10S403ATMA1	PG-TO263-7
IPD60N10S4-12	SP001102936	IPD60N10S412ATMA1	PG-TO252-3
IPD60N10S4L-12	SP000866550	IPD60N10S4L12ATMA1	PG-TO252-3
IPD90N10S4-06	SP001101896	IPD90N10S406ATMA1	PG-TO252-3
IPD90N10S4L-06	SP000866562	IPD90N10S4L06ATMA1	PG-TO252-3
IPG16N10S4-61	SP000892972	IPG16N10S461ATMA1	PG-TDSON-8
IPG16N10S4-61A	SP001091952	IPG16N10S461AATMA1	PG-TDSON-8
IPG16N10S4L-61A	SP001102932	IPG16N10S4L61AATMA1	PG-TDSON-8
IPG20N10S4-36A	SP001102930	IPG20N10S436AATMA1	PG-TDSON-8
IPG20N10S4L-22	SP000866570	IPG20N10S4L22ATMA1	PG-TDSON-8
IPG20N10S4L-22A	SP001091984	IPG20N10S4L22AATMA1	PG-TDSON-8
IPG20N10S4L-35	SP000859022	IPG20N10S4L35ATMA1	PG-TDSON-8
IPG20N10S4L-35A	SP001091928	IPG20N10S4L35AATMA1	PG-TDSON-8
IPI120N10S4-03	SP001102584	IPI120N10S403AKSA1	PG-TO262-3
IPI120N10S4-05	SP001102622	IPI120N10S405AKSA1	PG-TO262-3
IPP120N10S4-03	SP001102564	IPP120N10S403AKSA1	PG-TO220-3
IPP120N10S4-05	SP001102616	IPP120N10S405AKSA1	PG-TO220-3